

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
212740US-2SRD CONSERIAL NO.
New Continuation App.

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Yoshiyuki MATSUNAGA, et al.

FILING DATE

Herewith

GROUP

Unassigned

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
✓	AA 4,819,070	04/04/89	Hynecek			
✓	AB 5,144,447	09/01/92	Akimoto, et al.			
✓	AC 4,809,075	02/28/89	Akimoto, et al.			
✓	AD 5,172,249	12/15/92	Hashimoto			
✓	AE 4,942,474	07/17/90	Akimoto, et al.			
✓	AF 4,926,247	05/90	Nagasaki, et al.			
✓	AG 5,138,458	08/92	Nagasaki, et al.			
✓	AH 5,335,075	08/94	Komiya, et al.			
✓	AI 5,402,171	03/95	Tagami, et al.			
✓	AJ 5,343,254	08/94	Wada, et al.			
✓	AK RE 34,926	05/95	Hieda, et al.			
✓	AL 5,625,411	04/97	Inuiya, et al.			
✓	AM 4,805,025	02/89	Akiyama, et al.			
✓	AN 5,488,415	01/96	Uno			
✓	AO 6,091,449	07/00	Matsunaga, et al			
✓	AP 5,379,068	01/95	Hamasaki			
✓	AQ 5,793,423	08/98	Hamasaki			
✓	AR 5,187,583	02/93	Hamasaki			
✓	AS 5,322,994	06/94	Uno			
✓	AT 5,296,696	03/94	Uno			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	TRANSLATION NO
✓	AO 1-245769	09/29/89	Japan		X
✓	AP 6-217205	08/05/94	Japan		X
✓	AQ 1-238381	09/22/89	Japan		X
✓	AR WO97/07631	02/27/97	WIPO (English Abstract Only)	X	
✓	AS 5-207220	08/13/93	Japan		X
✓	AT 62-213485	09/19/87	Japan		X
✓	AU 6-350886	12/22/94	Japan		X
✓	AV 5-56357	03/05/93	Japan		X
✓	AW 5-37940	02/12/93	Japan		X
✓	AX 61-189785	08/23/96	Japan		X

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

✓	AZ	Chamberlain, Savvas G. "Photosensitivity and Scanning of Silicon Image Detector Arrays." IEEE, Journal of Solid-State Circuits, Vol. SC-4, No. 6, December 1969, pp. 333-342.
✓	BA	Patent Abstracts of Japan, Vol. 18, No. 535 (E-1615), October 12, 1994, JP 06 189199, July 8, 1994.
	BB	

Examiner

AUNG S. MOE

Date Considered

2/7/05

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.